

Figure S1. (a) C1s XPS spectra of GO and graphene film. (b) XRD patterns of GO, graphene and IOS α -Fe₂O₃/graphene film,

Samples Bonds	GO film	Graphene film
$A_{\rm C-O}/A_{\rm C-C/C=C}$	1.018	0.253
$A_{C=0}/A_{C-C/C=C}$	0.161	0.076
$A_{\text{OH-C=O}} / A_{\text{C-C/C=C}}$	0.019	

Table S1. The peak area (A) ratios of the oxygen-containing bonds to the C-C/C=C bonds for GO and graphene film.

The deconvoluted C1s peaks centered at the binding energies of 286.4, 286.6, 288.1, and 289.3 eV are assigned to the C-C/C=C, C-O, C=O and OH-C=O functional groups on the graphene oxide film surface, respectively [1]. After thermally reducing GO, the concentrations of these functional groups are remarkably decreased, the relative oxygen concentrations are calculated and summarized in Table S1.

The characteristic 20 peak of GO film appearing at 11.07° corresponds to a d-spacing of approximately 7.984 Å. the substantial shift of the (002) reflection from 7.98 to 3.6 Å after reduction processing of GO confirms the formation of graphene from GO. These diffraction peaks can be readily indexed to rhombohedral α -Fe₂O₃. Almost similar peaks are observed in the XRD pattern of FTO prove this analysis.

The Raman spectrum of GO film displays two prominent peaks: ~1352 and ~1594 cm⁻¹, which corresponds to the well-documented D and G bands, respectively. The second order Raman feature, the 2D band at ~2706 cm⁻¹ and D+G bands at ~2955 cm⁻¹ is very sensitive to the stacking order of the graphene sheets along the c-axis as well as to the number of layers. G and D bands correspond to the in-plane vibration of sp² bonded carbon atoms [2] and the presence of sp³ defects [3]. The intensity ratio for graphene film (1.175) shows an enhanced value compared to that for GO (0.752), indicating the presence of more localized sp3 defects within the sp2 carbon network after thermal reduction.



Figure S2. FE-SEM image of PS/graphene colloid templates.



Figure S3. EDS elemental maps with Fe, O and C of α -Fe₂O₃/graphene/FTO film.



Figure S4. FE-SEM images (a-c) and photograph (d) of different layered graphene thin film.

FE-SEM images of different layered graphene film, from Fig. S5, it is clear to see that the FTO substrate gradually become unclear with increasing spin-coating time.



Figure S5. Long term of stability for α -Fe₂O₃ and α -Fe₂O₃/graphene-5 photoanodes under closed circuit conditions at applied potential of 0.5 V.

Graphene coating time	Resistance (MΩ)
1	œ
2	œ
3	ω
4	œ
5	~15
6	~2

Table S2. Resistance of graphene thin film on glass with different spin-coating times.



Figure S6. AFM image of graphene thin film with spin coating of 5 times.



Figure S7. FE-SEM images of α -Fe₂O₃ film without any structure prepared by electrodeposition method.



Figure S8. IPCE results of inverse opal structure and general structure α -Fe₂O₃ at 0.5 V vs Ag/AgCl under illumination by AM 1.5G light in 1 M NaOH electrolyte.



Figure S9. Mott-Schottky plots of α -Fe₂O₃, IOS α -Fe₂O₃ and IOS α -Fe₂O₃/graphene-5 electrodes in 0.5 M NaOH electrolyte.

Reversed sigmoidal plots were observed with an overall shape relevant to typical for n-type α -Fe₂O₃ (Figure S7a). The flat-band voltage (Vfb), which was calculated to be 0.41, 0.39 and 0.09 V vs RHE in 0.5 M NaOH electrolyte (equivalent to 0.61, 0.59 and 0.29 V vs. NHE) from the x intercepts of the linear region corresponding to α -Fe₂O₃, IOS α -Fe₂O₃ and IOS α -Fe₂O₃/graphene-5 (Figure S7b). It is well-known that Vfb equals the Fermi Level (E_F) for n-type semiconductors, and is an inherent property of such semiconductors[4]. In addition, the calculated E_F of graphene is -0.08 eV vs NHE [5,6], which is more negative than the Fermi level of α -Fe₂O₃, resulting in hinder electron transfer from α -Fe₂O₃ to graphene. However, the accumulation of electrons inevitably causes shifting of the apparent Fermi level (E_F*) [7, 8], so that the Vfb of IOS α -Fe₂O₃/graphene-5 shifts negatively compared to that of IOS α -Fe₂O₃. On the other band, the E_F of FTO is negative enough to accept electrons from α -Fe₂O₃ excited. Thus, the electronic interaction between graphene/FTO substrate and IOS α -Fe₂O₃ may cause a cathodic shift of the EF*, resulting in a higher conduction band position which allows charge transfer from α -Fe₂O₃ to graphene.



Figure S10. Dark current of IOS α -Fe₂O₃ and IOS α -Fe₂O₃/graphene-5 electrodes in 0.5 M NaOH electrolyte.

Reference

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